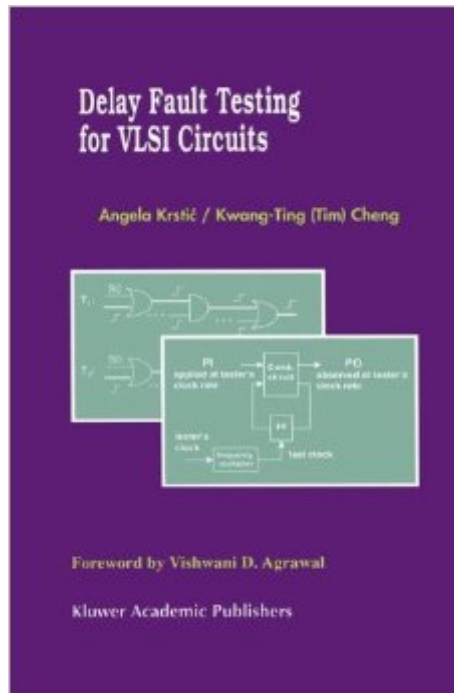


The book was found

Delay Fault Testing For VLSI Circuits (Frontiers In Electronic Testing)



Synopsis

In the early days of digital design, we were concerned with the logical correctness of circuits. We knew that if we slowed down the clock signal sufficiently, the circuit would function correctly. With improvements in the semiconductor process technology, our expectations on speed have soared. A frequently asked question in the last decade has been how fast can the clock run. This puts significant demands on timing analysis and delay testing. Fueled by the above events, a tremendous growth has occurred in the research on delay testing. Recent work includes fault models, algorithms for test generation and fault simulation, and methods for design and synthesis for testability. The authors of this book, Angela Krstic and Tim Cheng, have personally contributed to this research. Now they do an even greater service to the profession by collecting the work of a large number of researchers. In addition to expounding such a great deal of information, they have delivered it with utmost clarity. To further the reader's understanding many key concepts are illustrated by simple examples. The basic ideas of delay testing have reached a level of maturity that makes them suitable for practice. In that sense, this book is the best x DELAY FAULT TESTING FOR VLSI CIRCUITS available guide for an engineer designing or testing VLSI systems. Techniques for path delay testing and for use of slower test equipment to test high-speed circuits are of particular interest.

Book Information

Series: Frontiers in Electronic Testing (Book 14)

Hardcover: 191 pages

Publisher: Springer; 1998 edition (October 31, 1998)

Language: English

ISBN-10: 0792382951

ISBN-13: 978-0792382959

Product Dimensions: 6.1 x 0.5 x 9.2 inches

Shipping Weight: 1.1 pounds (View shipping rates and policies)

Average Customer Review: 5.0 out of 5 stars See all reviews (1 customer review)

Best Sellers Rank: #2,059,819 in Books (See Top 100 in Books) #82 in Books > Engineering & Transportation > Engineering > Electrical & Electronics > Circuits > VLSI & ULSI #326 in Books > Computers & Technology > Programming > Software Design, Testing & Engineering > Logic #633 in Books > Engineering & Transportation > Engineering > Electrical & Electronics > Circuits > Design

Customer Reviews

This book is the ultimate reference on testing for VLSI circuits. It is a must have if your interest is in delay testing. It is truly superbly written.

[Download to continue reading...](#)

Delay Fault Testing for VLSI Circuits (Frontiers in Electronic Testing) Electronic Circuits: The Definitive Guide to Circuit Boards, Testing Circuits and Electricity Principles Circuits, Interconnections, and Packaging for Vlsi (Addison-Wesley VLSI systems series) CMOS SRAM Circuit Design and Parametric Test in Nano-Scaled Technologies: Process-Aware SRAM Design and Test (Frontiers in Electronic Testing) CMOS VLSI Design: A Circuits and Systems Perspective (3rd Edition) CMOS VLSI Design: A Circuits and Systems Perspective Introduction to VLSI Circuits and Systems VLSI Design Techniques for Analog and Digital Circuits (McGraw-Hill Series in Electrical Engineering) PSPICE and MATLAB for Electronics: An Integrated Approach, Second Edition (VLSI Circuits) CMOS Nanoelectronics: Analog and RF VLSI Circuits VLSI Analog Signal Processing Circuits: Algorithm, Architecture, Modeling, and Circuit Implementation Low-Voltage/Low-Power Integrated Circuits and Systems: Low-Voltage Mixed-Signal Circuits (IEEE Press Series on Microelectronic Systems) Advances in 3D Integrated Circuits and Systems (Series on Emerging Technologies in Circuits and Systems) Principles of Transistor Circuits, Eighth Edition: Introduction and guide to the design of amplifiers, function generators, receivers and digital circuits Design of 3D Integrated Circuits and Systems (Devices, Circuits, and Systems) Evolutionary Electronics: Automatic Design of Electronic Circuits and Systems by Genetic Algorithms (International Series on Computational Intelligence) Foundations of Analog and Digital Electronic Circuits (The Morgan Kaufmann Series in Computer Architecture and Design) Electronic Circuits for the Evil Genius 2/E Electronic Materials Science: For Integrated Circuits in Si and GaAs Tolerance Analysis of Electronic Circuits Using MATHCAD

[Dmca](#)